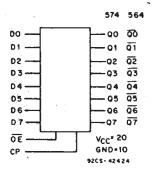
Data sheet acquired from Harris Semiconductor SCHS292



Octal D-Type Flip-Flop, 3-State Positive-Edge-Triggered

CD54/74AC/ACT564 - Inverting CD54/74AC/ACT574 - Non-Inverting

Type Features:

- Buffered inputs
- Typical propagation delay: 6.5 ns @ V_{CC} = 5 V, T_A = 25° C, C_L = 50 pF

FUNCTIONAL DIAGRAM

The RCA-CD54/74AC564 and CD54/74AC574 and the CD54/74ACT564 and CD54/74ACT574 octal D-type, 3-state, positive-edge-triggered flip-flops use the RCA ADVANCED CMOS technology. The eight flip-flops enter data into their registers on the LOW-to-HIGH transition of the clock (CP). The Output Enable (OE) controls the 3-state outputs and is independent of the register operation. When the Output Enable (OE) is HIGH, the outputs are in the high-impedance state. The CD54/74AC/ACT564 and CD54/74AC/ACT574 share the same pin configurations; the CD54/74AC/ACT564, however, has inverted outputs and the CD54/74AC/ACT574 has non-inverted outputs.

The CD74AC/ACT564 and CD74AC/ACT574 are supplied in 20-lead dual-in-line plastic packages (E suffix) and in 20-lead dual-in-line small-outline plastic packages (M suffix). Both package types are operable over the following temperature ranges: Commercial (0 to 70°C); Industrial (-40 to +85°C); and Extended Industrial/Military (-55 to +125°C).

The CD54AC/ACT564 and CD54AC/ACT574, available in chip form (H suffix), are operable over the -55 to +125°C temperature range.

Family Features:

- Exceeds 2-kV ESD Protection MIL-STD-883, Method 3015
- SCR-Latchup-resistant CMOS process and circuit design
- Speed of bipolar FAST*/AS/S with significantly reduced power consumption
- Balanced propagation delays
- AC types feature 1.5-V to 5.5-V operation and balanced noise immunity at 30% of the supply
- ± 24-mA output drive current
 - Fanout to 15 FAST* ICs
 - Drives 50-ohm transmission lines

*FAST is a Registered Trademark of Fairchild Semiconductor Corp.

TRUTH TABLE

	INPUTS	PUTS			
			564	574	
ŌĒ	СР	Dn	Qn	Qn	
L		Н	L	Н	
L		L	Н	L	
L	L	Х	QΘ	QO	
Н	Х	Х	Z	Z	

H = High level (steady state)

L = Low level (steady state)

X = Don't care

_/ = Transition from low to high level

QO = The level of Q before the indicated steady-state input conditions were established

QO = The level of Q before the indicated steady-state input conditions were established.

Z = High impedance

This data sheet is applicable to the CD54/74AC574 and CD54/74AC574. The CD54/74AC564 and CD54/74ACT564 were not acquired from Harris Semiconductor.

to 6 V
20 mA
50 mA
50 mA
) mÁ'
0 mW
0 mW
0 mW
0 mW
25°C
150°C
265°C
300°C

RECOMMENDED OPERATING CONDITIONS:

For maximum reliability, normal operating conditions should be selected so that operation is always within the following ranges:

	LIMITS			LINUTC
CHARACTERISTIC		MIN.	MAX.	UNITS
Supply-Voltage Range, Vcc*:				
(For $T_A = Full Package-Temperature Range)$			l	
AC Types		1.5	5.5	V
ACT Types		4.5	5.5	V
DC Input or Output Voltage, V ₁ , V ₀		0	Vcc	V
Operating Temperature, T _A :		-55	+125	°C
Input Rise and Fall Slew Rate, dt/dv				
at 1.5 V to 3 V (AC Types)		0	50	ns/V
at 3.6 V to 5.5 V (AC Types)		0	20	ns/V
at 4.5 V to 5.5 V (ACT Types)		0	10	ns/V

^{*}Unless otherwise specified, all voltages are referenced to ground.

TERMINAL ASSIGNMENT DIAGRAMS



CD54/74AC/ACT564

CD54/74AC/ACT574

STATIC ELECTRICAL CHARACTERISTICS: AC Series

,						AMBIENT TEMPERATURE (TA) - °C					
CHARACTERISTICS		TEST CO	TEST CONDITIONS		V _{cc} +		-40	to +85	-55 t	o +125	UNITS
		. V, (V)	l _o (mA)	(V)	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
High-Level Input				1.5	1.2	1 –	1.2	_	1.2	1-	
Voltage	V _{IH}			3	2.1	-	2.1	_	2.1	_	1 v
				5.5	3.85	_	3.85	_	3.85		1
Low-Level Input				1.5	_	0.3	_	0.3	-	0.3	-
Voltage	VIL			3	_	0.9		0.9	_	0.9	l v
				5.5		1.65	T -	1.65	_	1.65	1
High-Level Output		· · · · · ·	-0.05	1.5	1.4	T -	1.4		1.4		,
Voltage	V _{OH}	V _{IH}	-0.05	3	2.9		2.9		2.9	T =	1
	•	or	-0.05	4.5	4.4		4.4		4.4	T	1
		V _{IL}	-4	3	2.58	_	2.48	_	2.4		l v
	-		-24	4.5	3.94	-	3.8	_	3.7		1
			-75	5.5			3.85		_	_	1
		#. * {	-50	5.5	_		<u> </u>		3.85	_	1
Low-Level Output			0.05	1.5	_	0.1		0.1	_	0.1	
Voltage	Vol	V _{IH}	0.05	3	_	0.1	_	0.1	_	0.1	
		or	0.05	4.5	_	0.1	_	0.1	_	0.1	v
		V _{IL}	12	3	_	0.36	_	0.44	_	0.5	
			24	4.5	_	0.36	_	0.44	_	0.5	
			75	5.5	_	_	_	1.65	_	_	
		#, * {	50	5.5		_	<u> </u>	_	_	1.65	
Input Leakage Current	I _t	V _{cc} or GND		5.5	-	±0.1		±1	_	±1	μΑ
3-State Leakage		ViH									
Current	loz	or									
		VıL									
		' Vo =		5.5	_	±0.5	_	±5		±10	μΑ
		Vcc								٠ .	•
		or									
		GND									
Quiescent Supply Current, MSI	lcc	V _{cc} or GND	0	5.5		8	_	80		160	μΑ

[#]Test one output at a time for a 1-second maximum duration. Measurement is made by forcing current and measuring voltage to minimize power dissipation.
*Test verifies a minimum 50-ohm transmission-line-drive capability at +85°C, 75 ohms at +125°C.

STATIC ELECTRICAL CHARACTERISTICS: ACT Series

						AMBIEN	T TEMPE	RATURE	(T _A) - °	С	
CHARACTERISTICS		TEST CONDITIONS		V _{cc}	+25		-40 t	o +85	-55 to	o.+125 UNIT	
		(V)	l _o (mA)	(V)	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	UNITS
High-Level Input Voltage	V _{IH}			4.5 to 5.5	2	_	2		2	_	V
Low-Level Input Voltage	Vil			4.5 to 5.5	_	0.8	_	0.8	_	0.8	V
High-Level Output		V _{IH}	-0.05	4.5	4.4		4.4	_	4.4	_	
Voltage	V _{OH}	or "	-24	4.5	3.94	_	3.8	-	3.7	_	l v
		VII. }	-75	5.5	_		3.85		_	Ī —	1 "
		#, * {	-50	5.5	1-	_	_	<u> </u>	3.85	_	1
Low-Level Output		V _{IH}	0.05	4.5		±0.1		±.1	_	±.1	
Voltage	Vol	or	24	4.5	_	0.36	_	0.44	_	0.5] v
	:	Vil s	75	5.5	_			1.65	_	_	
		#, * {	50	5.5	-	_	_	_	_	1.65	
Input Leakage Current	tı	V _{cc} or GND		5.5	_	±0.1	_	±1	<u></u>	±1	μΑ
3-State Leakage Current	loz	V _{IH} or V _{IL} V _O = V _{CC} or		5.5	· · · · · · · · · · · · · · · · · · ·	±0.5	-	±5		±10	μΑ
Quiescent Supply Current, MSI	lcc	GND V _{CC} or GND	0	5.5		8	_	80		160	μΑ
Additional Quiescent Current per Input P TTL Inputs High 1 Unit Load	Supply in ΔIcc	V _{cc} -2.1		4.5 to 5.5	_	2.4	<u></u> :	2.8	_	3	mA

[#]Test one output at a time for a 1-second maximum duration. Measurement is made by forcing current and measuring voltage to minimize power dissipation.

ACT INPUT LOADING TABLE

INPUT	UNIT LOADS*
D, ŌĒ	0.7
CP	1.17

^{*}Unit load is ΔI_{CC} limit specified in Static Characteristics Chart, e.g., 2.4 mA max. @ 25°C.

^{*}Test verifies a minimum 50-ohm transmission-line-drive capability at +85°C, 75 ohms at +125°C.

PREREQUISITE FOR SWITCHING: AC Series

				ENT TEMP	ERATURE (Γ _Λ) -° C	
CHARACTERISTICS	SYMBOL	V _{cc}	-40 to +85				UNITS
· ·		(V)	MIN.	MAX.	MIN.	MAX.	
Clock Pulse Width	tw	1.5 3.3* 5†	44 4.9 3.5	=	50 5.6 4		ns
Setup Time Data to Clock	tsu	1.5 3.3 5	2 2 2	=	2 2 2		ns
Hold Time Data to Clock	ţ t H	1.5 3.3 5	2 2 2	=	2 2 2	 _ _	ns
Maximum Clock Frequency	f _{MAX}	1.5 3.3 5	11 101 143		10 89 125	_ _ _	MHz

*3.3 V: min. is @ 3 V †5 V: min. is @ 4.5 V

SWITCHING CHARACTERISTICS: AC Series; t_{rr} , t_{t} = 3 ns, C_{L} = 50 pF

				AMBIENT TEMPERATURE (TA) -°C				
CHARACTERISTICS	SYMBOL	V _{cc} (V)		to +85		0 +125	UNITS	
		(*)	MIN.	MAX.	MIN.	MAX.	1	
Propagation Delays: Clock to Q AC574	tpLH tpHL	1.5 3.3* 5†	_ 4 2.9	123 13.7 9.8	 3.8 2.7	135 15.1 10.8	ns	
Clock to Q AC564	t _{PLH} t _{PHL}	1.5 3.3 5	4.1 2.9	128 14.4 10.3	_ 4 2.8	141 15.8 11.3	ns	
Output Enable to Q, ቒ	t _{PZL} t _{PZH}	1.5 3.3 5	5.6 3.7	165 19.2 13.2	 5.5 3.6	181 21.8 14.5	ns	
Output Disable to Q, Q	t _{PLZ} t _{PHZ}	1.5 3.3 5	4.7 3.7	165 16.5 13.2	4.5 3.6	181 18.1 14.5	ns	
Power Dissipation Capacitance	C _{PD} §	_	67	Тур.	67	Гур.	pF	
Min. (Valley) V _{OH} During Switching of Other Outputs (Output Under Test Not Switching)	V _{онv} See . Fig. 1	5	4 Typ. @ 25°C				v	
Max. (Peak) Vol. During Switching of Other Outputs (Output Under Test Not Switching)	V _{OLP} See Fig. 1	5	1 Typ. @ 25°C			٧		
Input Capacitance	Cı			10	_	10	pF	
3-State Output Capacitance	Co		_	15		15	pF	

*3.3 V: min. is @ 3.6 V max. is @ 3 V †5 V: min. is @ 5.5 V max. is @ 4.5 V

§CPD is used to determine the dynamic power consumption, per flip flop.

 $P_D = C_{PO} V_{CC}^2 f_i + \Sigma V_{CC}^2 f_0 C_L$ where $f_i = input$ frequency

fo = output frequency C_L = output load capacitance

V_{cc} = supply voltage.

Technical Data.

CD54/74AC564, CD54/74AC574 CD54/74ACT564, CD54/74ACT574

PREREQUISITE FOR SWITCHING: ACT Series

			AMBI	ENT TEMPE	RATURE (1	「A) -° C	
CHARACTERISTICS	SYMBOL	V _{cc}	V _{CC} -40 to		-55 to +125		UNITS
on more than the		(4)	MIN.	MAX.	MIN.	MAX.	
Clock Pulse Width	tw	5†	3.9	_	4.5	_	ns
Setup Time Data to Clock	t _{su}	5	2	<u> </u>	2	_	ns
Hold Time Data to Clock	t _H	5	2.6		3	_	ns
Maximum Clock Frequency	fmax	5	125		110		MHz

†5 V: min. is @ 4.5 V

SWITCHING CHARACTERISTICS: ACT Series; t,, t, = 3 ns, CL = 50 pF

			AMBIENT TEMPERATURE (TA) -°C				
CHARACTERISTICS	SYMBOL	V _{CC} -4		o +85	-55 to +125		UNITS
OTANAO TENISTIOS		(V)	MIN.	MAX.	MIN.	MAX.	
Propagation Delays: Clock to Q ACT574	tецн tенс	5†	2.9	10.2	2.8	11.2	ns
Clock to Q ACT564	t _{PLH} t _{PHL}	5	3	10.6	2.9	11.7	ns
Output Enable and Disable to Q ACT574	tplz tpHz tpZL tpZH	5	3.7	13.2	3.6	14.5	ns
Output Enable and Disable to Q ACT564	tplz tpHz tpzL tpzH	5	3.7	13.2	3.6	14.5	ns
Power Dissipation Capacitance	C _{PO} §		67	Тур.	67	Тур.	pF
Min. (Valley) V _{OH} During Switching of Other Outputs (Output Under Test Not Switching)	V _{онv} See Fig. 1	5	4 Typ. @ 25°C				V
Max. (Peak) Vol. During Switching of Other Outputs (Output Under Test Not Switching)	V _{OLP} See Fig. 1	5	1 Typ. @ 25°C		V		
Input Capacitance	Cı		-	10		10	pF
3-State Output Capacitance	Co	_		15		15	pF

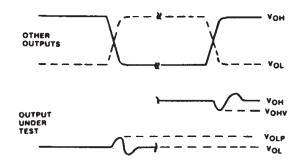
†5 V: min. is @ 5.5 V max. is @ 4.5 V

 $\S{C_{PD}}$ is used to determine the dynamic power consumption, per flip flop. $P_D = C_{PD} \ V_{CC}^2 \ f_i + \Sigma \ V_{CC}^2 \ f_0 \ C_L + V_{CC} \ \Delta I_{CC}$ where f_i = input frequency

 f_0 = output frequency C_L = output load capacitance

 $V_{cc} = supply voltage.$

PARAMETER MEASUREMENT INFORMATION



- VOHY AND VOLP ARE MEASURED WITH RESPECT TO A GROUND REFERENCE NEAR THE OUTPUT UNDER TEST.
 INPUT PULSES HAVE THE FOLLOWING CHARACTERISTICS:
- PRR \leq 1 MHz, $t_{\rm f}$ = 3 ns, $t_{\rm f}$ = 3 ns, SKEW 1 ns.
- 3. R.F. FIXTURE WITH 700-MHz DESIGN RULES REQUIRED.
 IC SHOULD BE SOLDERED INTO TEST BOARD AND BYPASSED WITH 0.1 µF CAPACITOR. SCOPE AND PROBES REQUIRE 700-MH2 BANDWIDTH.

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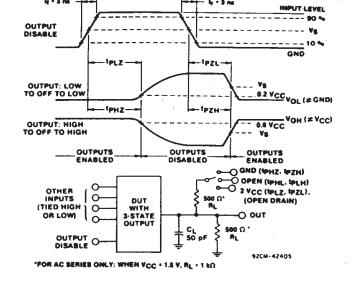
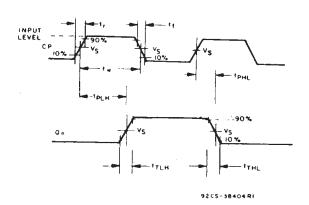
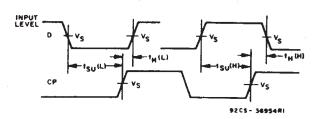
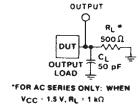


Fig. 1 - Simultaneous switching transient waveforms.

Fig. 2 - Three-state propagation delay waveforms and test circuit.







	CD54/74AC	CD54/74ACT
Input Level	V _{cc}	3 V
Input Switching Voltage, Vs	0.5 V _{CC}	1.5 V
Output Switching Voltage, Vs	0.5 V _{cc}	0.5 V _{CC}

Fig. 3 - Propagation delays times and test circuit.

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